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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
09/698,317	10/27/2000	Byung Jin Choi	PA09-06V02	6298	
75	90 02/20/2004		EXAM	INER	
Kenneth C. Br	ooks		DOUGHERTY	, THOMAS M	
Molecular Impr Legal Dept.	ints, Inc.		ART UNIT	PAPER NUMBER	
P.O. Box 81536			2834		
Austin, TX 78	708		DATE MAILED: 02/20/2004		

Please find below and/or attached an Office communication concerning this application or proceeding.

7	Application No.	Applicant(s)
	09/698,317	CHOI ET AL.
Office Action Summary	Examiner	Art Unit
	Thomas M. Dougherty	2834
The MAILING DATE of this communication app Period for Reply	pears on the cover sheet with the c	orrespondence address
A SHORTENED STATUTORY PERIOD FOR REPL' THE MAILING DATE OF THIS COMMUNICATION. - Extensions of time may be available under the provisions of 37 CFR 1.1 after SIX (6) MONTHS from the mailing date of this communication. - If the period for reply specified above is less than thirty (30) days, a repl - If NO period for reply is specified above, the maximum statutory period of the period for reply within the set or extended period for reply will, by statute any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b).	36(a). In no event, however, may a reply be time y within the statutory minimum of thirty (30) days will apply and will expire SIX (6) MONTHS from the cause the application to become ABANDONE	nely filed s will be considered timely. the mailing date of this communication. D (35 U.S.C. § 133).
Status		
1) Responsive to communication(s) filed on 28 N	lovember 2003.	
2a) This action is FINAL . 2b) ☑ This	s action is non-final.	
3) Since this application is in condition for alloware closed in accordance with the practice under E	•	
Disposition of Claims		
4) ⊠ Claim(s) <u>77-103</u> is/are pending in the applicati 4a) Of the above claim(s) <u>87-103</u> is/are withdra 5) ☐ Claim(s) is/are allowed. 6) ☒ Claim(s) <u>77 and 86</u> is/are rejected. 7) ☒ Claim(s) <u>78-85</u> is/are objected to. 8) ☐ Claim(s) are subject to restriction and/o	awn from consideration.	
Application Papers		
9)☐ The specification is objected to by the Examine	er.	
10) The drawing(s) filed on is/are: a) acc	epted or b) objected to by the E	Examiner.
Applicant may not request that any objection to the	drawing(s) be held in abeyance. See	37 CFR 1.85(a).
Replacement drawing sheet(s) including the correct 11) The oath or declaration is objected to by the Ex	, , , , , , , , , , , , , , , , , , , ,	• •
Priority under 35 U.S.C. § 119		
12) Acknowledgment is made of a claim for foreign a) All b) Some * c) None of: 1. Certified copies of the priority document 2. Certified copies of the priority document 3. Copies of the certified copies of the priority document application from the International Bureau * See the attached detailed Office action for a list	s have been received. s have been received in Application rity documents have been receive u (PCT Rule 17.2(a)).	on No ed in this National Stage
Attachment(s)		
1) Notice of References Cited (PTO-892)	4) Interview Summary	
 Notice of Draftsperson's Patent Drawing Review (PTO-948) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08) Paper No(s)/Mail Date 602,203,1203. 	Paper No(s)/Mail Da 5) Notice of Informal Pa 6) Other:	te atent Application (PTO-152)

Art Unit: 2834

DETAILED ACTION

Drawings

The drawings have been noted as being informal by the Applicants. The proposed changes to the drawings in the paper of 07/07/03 is approved by the Examiner.

Claim Rejections - 35 USC § 102

The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

(e) the invention was described in (1) an application for patent, published under section 122(b), by another filed in the United States before the invention by the applicant for patent or (2) a patent granted on an application for patent by another filed in the United States before the invention by the applicant for patent, except that an international application filed under the treaty defined in section 351(a) shall have the effects for purposes of this subsection of an application filed in the United States only if the international application designated the United States and was published under Article 21(2) of such treaty in the English language.

Claims 77 and 86 are rejected under 35 U.S.C. 102(e) as being anticipated by Suzuki et al. (US 6,411,010). Suzuki et al. show (fig. 7) a device to orientate a body (303) with respect to a surface (301) spaced apart from said body (303), said device comprising: a flexure system (304); and a body (303) connected to said flexure system (304), with said flexure system (304) adapted to position said body (303) in a desired orientation with respect to said surface (301) and maintain said orientation in response to a force being exerted upon said body (303).

Said flexure system (304) further comprise a plurality of piezo actuators (306a-d) attached to apply a force to rotate said body (303).

Allowable Subject Matter

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Art Unit: 2834

Claims 78-85 are objected to as being dependent upon a rejected base claim, but would be allowable if rewritten in independent form including all of the limitations of the base claim and any intervening claims.

The following is an examiner's statement of reasons for allowance: the prior art fails to show or fairly suggest a pair of flexure members, each for orientation of the body and each defining its own axis of rotation wherein the two axes of rotation extend transversely to each other and the two axes are decoupled from each other. Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Response to Arguments

Applicant's arguments filed 11/28/03 have been fully considered but they are not persuasive. The restriction is maintained for the reasons cited in the restriction requirement.

Conclusion

The prior art made of record and not relied upon is considered pertinent to applicant's disclosure. The remaining prior art cited reads on at least some aspect or aspects of the claimed invention.

Direct inquiry to Examiner Dougherty at (571) 272-2022.

February 13, 2004

THOMAS M. DOUGHERAN PRIMARY EXAMINER GROUP 2100

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Substitute for form 1449A/PTO

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INFORMATION DISCLOS STATEMENT BY APP

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of

Complete if Known **Application Number** 09/698,317 Filing Date October 27, 2000 First Named Inventor Choi et al. 2859 Broup Art Unit Examiner Name Unassigned T. Doug

Attorney Docket Number PA09-06V02

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				U.S. PATENT DOCUMEN	TS	
Examiner Initials*	Cite No.	. U.S. Patent D	ocument Kind Code ^z (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
Carl	B1	4,440,804		Milgram	04-03-1984	
Ten	B2	4,544,572		Sandvig et al.	10-01-1985	
TWO	B3	5,723,176		Keyworth et al.	03-03-1998	
mo	B4	5,747,102		Smith et al.	05-05-1998	
m	B5	6,125,183		Jiawook et al.	09-26-2000	
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	FOREIGN PATENT DOCUMENTS									
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Examiner Initials*	Cite No.1	Office ³	Number ⁴	Kind Code ⁵ (if known)	Name of Patentee or Applicant of Cited Document	Cited Document MM-DD-YYYY	Where Relevant Passages or Relevant Figures Appear	1		
CMI	B6	wo	92/17883		Olsson	10-15-1992		T		
DWD	B7	wo	98/10121		Olsson et al.	03-12-1998		十		
mo	B8	wo	99/45753		Wikström	09-10-1999		†		
Tinn	B9	wo	99/63535		Olsson	12-09-1999		+		
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*EXAMINER: Initial if reference considered, whether or not station is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹Unique citation designation number. ²See attached Kinds of U.S. Patent Documents. ³Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶Applicant is to place a check mark here if English language Translation is attached.

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ond to a collection of information unless it displays a valid OMB control number. Complete if Known Substitute for form 1449B/PTO **Application Number** 09/698,317 **INFORMATION DISCLOSURE** October 27, 2000 **Filing Date** STATEMENT BY APPLICANT **First Named Inventor** Choi et al. 2859 Group Art Unit (use as many sheets as necessary) **Examiner Name** Unassigned 7 2 2

Attorney Docket Number

OTHER PRIOR	R ART -	NON PATENT LITERATURE DOCUMENTS					
Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.					
	B10	LIN, "Multi-Layer Resist Systems", Introduction of Microlithography", American Chemical Society, 1983, pp.					
TMB		287-350, IBM T.J. Watson Research Center, Yorktown Heights, New York 10598.					
	B11	COWIE, "Polymers: Chemistry and Physics of Modern Materials", 1991, pp. 408-409, 2 nd Ed, Chapman and					
mo		Hall, a division of Routledge, Chapman and Hall, Inc., 29 West 35 th Street, NY, NY 10001-2291.					
	B12	CHOU et al., "Imprint of Sub-25 nm Vias and Trenches in Polymers", Applied Physics Letters, November					
TMD	,	20, 1995, pp. 3114-3116, vol. 67(21).					
	B13	CHOU et al., "Imprint Lithography with 25-Nanometer Resolution", Science, Apr. 5, 1996, pp. 85-87, vol.					
am	-	272.					
	B14	CHOU et al., "Imprint Lithography with Sub-10nm Feature Size and High Throughput", Microelectronic					
amt		Engineering, 1997, pp. 237-240, vol. 35.					
	B15	XIA et al., "Soft Lithography", Agnew. Chem. Int. Ed., 1998, pp. 550-575, vol. 37.					
CMT		XIA et al., "Soft Lithography", Agnew. Chem. Int. Ed., 1998, pp. 550-575, vol. 37.	77				
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Signature	Thomas M. Sucherto	Considered	2-12-07

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹Unique citation designation number. ²Applicant is to place a check mark here if English language Translation is attached.

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Complete if Known Substitute for form 1449A/PTO Application Numb r 09/698,317 ANFORMATION DISCLOSURE **Filing Date** October 27, 2000 TATEMENT BY APPLICANT First Named Inventor Choi et al. Group Art Unit 2834 (use as many sheets as necessary) **Examiner Name** Dougherty, Thomas M.

Attorney Docket Number

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				U.S. PATENT DOCUMEN	TS	
Examiner Initials*	Cite No.	U.S. Patent Document Kind Code* Number (# known)		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
MD	C1	4,326,805		Feldman et al.	04-27-1982	
MD	C2	4,724,222		Feldman et al.	02-09-1988	
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^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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PTO/SB/08A (08-00)

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Debruary 12, 2004

¹Unique citation designation number. ²See attached Kinds of U.S. Patent Documents. ³Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ¹For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶Applicant is to place a check mark here if English language Translation is attached.

U.S. Patent and Trademark Office; U.S. DEPARTMENT OF COMMERCE

	Substitute for form 1449B/PTO					Complete if Known		
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OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS								
Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country.where published. Feldman et al., "Wafer Chuck for Magnification correction in X-ray Lithography," Journal of Vacuum Science						
	СЗ	Feldman et al., "Wafer Chuck for Magnification correction in X-ray Lithography," Journal of Vacuum Science						
TWO		and Technology, Nov/Dec 1998, pp. 3476-3479, vol. B 16(6).						
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JUN 2002

Form PTO-1449 (modified)
List of Patents and Publication ADEN

For Applicant's Information

Disclosure Statement
(Use several sheets if necessary)

ATTY. DKT. NO. 5119-08601

APPLICANT: Choi et al.

SERIAL NO. 09/698,317

GROUP: 2859

FILING DATE: October 27, 2000

U.S. PATENT DOCUMENTS

EXAM. INITIALS	REF. DES.	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
true	A1	3,807,027	4/1974	Heisler	29	423	
ymy	A2	3,807,029	4/1974	Troeger	29	436	
MND	A3	3,811,665	5/1974	Seelig	267	ECEI	VED
trus	A4	4,062,600	12/1977	Wyse	384	7985 B	2002
and	A5	4,098,001	7/1978	Watson	33	644	0000
(m)	A6	4,155,169	5/1979	Drake et al.	335	LAMP	3600
mo	A7	4,202,107	5/1980	Watson	33	644	
MM	A8	4,267,212	5/1981	Sakawaki	427	240	
my	A9	4,337,579	7/1982	De Fazio	33	644	
my	A10	4,355,469	10/1982	Nevins et al.	267	150	
my	All	4,414,750	11/1983	De Fazio	267	166	
Jul	A12	4,451,507	5/1984	Beltz et al.	427	240	
IMA	A13	4,610,442	9/1986	Oku et al.	269	73	
my	A14	4,694,703	11/1987	Routson	74	5 F	
my	A15	4,731,155	3/1988	Napoli et al.	216	44	
am	A16	4,763,886	8/1988	Takei	269	73	
mo	A17	4,929,083	5/1990	Brunner	356	400	
am	A18	4,959,252	11/1990	Bonnebat et al.	428	64.7	
mo	A19	5,072,126	12/1991	Progler	250	548	
· My	A20	5,110,514	5/1992	Soane	264	496	
mo	A21	5,126,006	6/1992	Cronin et al.	H38	70Z	
mo	A22	5,204,739	4/1993	Domenicali	348	79	
tmo	A23	5,240,550	8/1993	Boehnke et al.	216	24	
tmp	A24	5,348,616	9/1994	Hartman et al.	216	48	
rub	A25	5,392,123	2/1995	Marcus et al.	356	625	
dut	A26	5,425,964	6/1995	Southwell et al.	427	10	
ans	A27	5,452,090	9/1995	Progler et al.	356	401	

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Meman M. Konglant

DATE CONSIDERED:

Zeb. 13, 2009

Form PTO-1449 (modified PE

List of Patents and Publications' For Applicant's Information

Disclosure Statement

(Use several sheets if necessary)

ATTY. DKT. NO. 5119-08601

APPLICANT: Choi et al.

SERIAL NO. 09/698,317

GROUP: 2859

FILING DATE: October 27, 2000

PATENT DOCUMENTS								
EXAM. INITIALS	REF. DES.	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE	
Tmo	A28	5,480.047	1/1996	Tanigawa et al.	216	12		
mp	A29	5,512,131	4/1996	Kumar et al.	438	BEEF	IVED	
mo	A30	5,515,167	5/1996	Ledger et al.	356	595 2		
Mb	A31	5,545,367	10/1996	Bae et al.	ZU	HAL.	2002	
· my	A32	5,566,584	10/1996	Briganti et al.	744	496.9F	3600	
mb	A33	5,633,505	5/1997	Chung et al.	250	491.1	- 50	
mb	A34	5,724,145	3/1998	Kondo et al.	356	632		
mb	A35	5,753,014	5/1998	Van Rijn	96	12		
the	A36	5,760,500	6/1998	Kondo et al.	310	12		
mo	A37	5,772,905	6/1998	Chou	216	44		
mb	A38	5,776,748	7/1998	Singhvi et al.	435	180	,	
TMP	A39	5,779,799	7/1998	Davis	118	663		
try	A40	5,802,914	9/1998	Fassler et al.	74	110		
trus	A41	5,877,036	3/1999	Kawai	438	16		
Mos	A42	5,877,861	3/1999	Ausschnitt et al.	3 56	401		
The	A43	5,888,650	3/1999	Calhoun et al.	428	354		
Try	A44	5,900,160	5/1999	Whitesides et al.	216	41		
mo	A45	5,912,049	6/1999	Shirley	427	240		
True	A46	5,942,871	8/1999	Lee	318	611		
mo	A47	5,948,470	9/1999	Harrison et al.	427	198		
nuo	A48	5,952,127	9/1999	Yamanaka	430	5		
mo	A49	6,038,280	3/2000	Rossiger et al.	378	50		
imp	A50	6,039,897	3/2000	Lochhead et al.	264	1,24		
m	A51	6,046,056	4/2000	Parce et al.	204	403.05		
mn	A52	6,051,345	4/2000	Huang	430	5		
MNO	A53	6,074,827	6/2000	Nelson et al.	735	6		
mn	A54	6,091,485	7/2000	Li et al.	356	13		
	A55	6,128,085	10/2000	Buermann et al.	356	-369		

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DATE CONSIDERED:

Leb. 13, 2004

Form PTO-1449 (modified)
List of Patents and Publications
For Applicant's Information
Disclosure Statement
(Use several sheets if necessary)

ATTY. DKT. NO. 5119-08601

APPLICANT: Choi et al.

SERIAL NO. 09/698,317

GROUP: 2859

FILING DATE: October 27, 2000

S.S.	PA	TENT	DOC	UN	MENTS
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EXAM. INITIALS	REF. DES.	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
amy	A56	6,143,412	11/2000	Schueller et al.	428	BEC) [] / [_
my	A57	6,168,845	1/2001	Fontana, Jr. et al.	428	65.5	FIVED
ami	A58	6,180,239	1/2001	Whitesides et al.	728	411. PUN	2 6 2002
mo	A59	6,204,922	3/2001	Chalmers	356	GROI	JP 3600
my	A60	6,334,960	1/2002	Wilson et al.	216	52	יי טטטנ
		FOR	EIGN PATE	ENT DOCUMENTS			
EXAM. INITIALS	REF. DES.	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION YES/NO
Janes	A61	00/54107	9/2000	wo	60°F	7/00	
mo	A62	01/33232	5/2001	WO	601R	—	
Mil	A63	01/33300	5/2001	WO	HO2K	5/24	
mo	A64	244884	3/1987	EP	829C	33/34	
mis	A65	733455	9/1996	EP	BZ9C	33/34	NO
min	A66	2800476	7/1978	DE	603C	5/08	NO
MB	A67	19648844	11/1999	DE	829C	59/02	NO
MD	A68	1-196749	8/1989	л	GIIB	7/26	NO

EXAMINER: Thomas M. Loughetty DATE CONSIDERED: 7etr. 13, 2004

List o	Form PTO-1449 (modes 1) PE ATTY. DKT. NO. 5119-08601 List of Patents and Publications APPLICANT. Classical Page 197698,317							
List of Patents and Publications For Applicant's Information Disclosure Statement July 2 1 2002 APPLICANT: Choi et al. GROUP: 2859 GROUP: 2859 GROUP: 2859 GROUP: 2859								
(U	(Use several sheets if neckstery) FILING DATE: October 27, 2000 GROUP							
		OTHER ARIT (Including Author, Title, Date, Pertinent Pages, Etc.)						
dut.	A69	Stewart, D.; "A Platform with Six Degrees of Freedom", Proc. of Inst. Mech. Engrs., 1965, 180, 371-378.						
mb	A70	Paros, J.M.; Weisbord, L.; "How to Design Flexure Hinges", Machine Design, 1965, 151-156.						
M	A71	Raibert, M.H.; Craig, J.J.; "Hybrid Position/Force Control of Manipulators", 1981, 102, 126-133.						
mp	A72	Hogan, Neville; "Impedance Control: An Approach to Manipulation", Journal of Dynamic Systems, Measurement and Control, 1985, 107, 1-7.						
They	A73	Hollis, Ralph; Salcudean, S.E.; Allan, A.P.; "A Six-Degree-of-Freedom Magnetically Levitated Variable Compliance Fine-Motion Wrist: Design, Modeling and Control", IEEE Transactions on Robotics and Automation, 1991, 7, 320-332.						
my	A74	Tomita, Y. et al.; "6-Axes Motion Control Method for Parallel-Linkage-Type Fine Motion Stage", Journal of Japan Society of Precision Engineering, 1992, 118-124.						
MD	A75	Slocum, Alexander; "Precision Machine Design: Macromachine Design Philosophy and its Applicability to the Design of Micromachines", Proc. of IEEE Micro Electro Mech. Systems Workshop, 1992, 37-42.						
mo	A76	Krug, Herbert; Merl, Norbert; Schmidt, Helmut; "Fine Patterning of Thin Sol-Gel Films", Journal of Non-Crystalline Solids, 1992, 447-450.						
my	A77	Arai, T.; Larsonneur, R.; Jaya, Y.M.; "Calibration and Basic Motion of a Micro Hand Module", Proc. of IECON, 1993, 1660-1665.						
mp	A78	Peng, Zhi-Xin; Adachi, N.; "Compliant Motion Control of Kinematically Redundant Manipulators", IEEE Transactions on Robotics and Automation, 1993, 9, 831-837.						
tmb	A79	Rong, Y.; Zhu, Y.; Luo, Z.; Liu, X.; "Design and Analysis of Flexure-Hinge Mechanism Used in Micro-Positioning Stages", ASME, 1994, 2, 979-985.						
ans	A80	Hashimoto, M.; Imamura, Y.; "Design and Characteristics of a Parallel Link Compliant Wrist", IEEE International Conference on Robotics and Automation, 1994, 2457-2462.						
trub	A81	Merlet, J.P.; "Parallel Manipulators: State of the Art and Perspectives", Advanced Robotics, 1994, 8, 589-596.						
. my	A82	Ananthasuresh, S.; Kikuchi, N.; "Strategies for Systematic Synthesis of Compliant MEMS", ASME, 1994, 2, 677-686.						
mp	A83	Arai, T.; Tanikawa, T.; Merlet, J.P.; Sendai, T., "Development of a New Parallel Manipulator with Fixed Linear Actuator", Proc. of Japan/USA Symposium on Flexible Automation, 1996, 1, 145-149.						
mn	A84	Howell, L.L.; Midha, A.; "Loop-Closure Theory of the Analysis and Synthesis of Compliant Mechanisms", Journal of Mechanical Design, 1996, 118, 121-125.						
my	A85	Haisma, J. et al.; "Mold-Assisted Nanolithography: A Process for Reliable Pattern Replication", Journal of Vacuum Science and Technology, 1996, 14, 4124-4128.						
mo	A86	Pernette, Eric; Henein, Simon; Magnani, Ivo; Clavel, Reymond; "Design of Parallel Robots in Microrobotics", Robotica, 1997, 15, 417-420.						
XAMINER:		Comas M. Gergland DATE CONSIDERED: 2et. 13, 2004						

		Page 5 of C
List o For	of Pate Appli Disclo	TO-1449 (modified) F ATTY. DKT. NO. 5119-08601 Ints and Publications cant's Information 2 APPLICANT: Choi et applications sure Statement al sheets if necessary) FILING DATE: October 27, 2000 FILING DATE: October 27, 2000 FILING DATE: October 27, 2000
tmo	A87	Rong, L.; Guanghead Dynamics of Parallel Mechanism with Direct Compliance Control", IEEE, 1997, 1753-1758.
Tmin	A88	Mittal, Samir; Menq, Chia-Hsiang; "Precision Motion Control of Magnetic Suspension Actuator Using a Robust Nonlinear Compensation Scheme", IEEE/ASME Transactions on Mechatronics, 1997, 2, 268-280.
gnet	A89	Physik Instruments, Product Catalog for Micropositioning, 1997.
mb	A90	Williams, Mark et al.; "Six Degree of Freedom Mag-Lev Stage Development", SPIE, 1997, 3051, 856-867.
·tmin	A91	Lee, Chang-Woo; Kim, Seung-Woo; "Ultraprecision Stage for Alignment of Wafers in Advanced Microlithography", Precision Engineering, 1997, 21, 113-122.
my	A92	Kanetomo, M.; Kashima, H.; Suzuki, T.; "Robot for Use in Ultrahigh Vacuum", Solid State Tech., 1997, 63-72.
mp	A93	Goldfarb, M.; Speich, J.; "Compliant Micromanipulator Design for Scaled Bilateral Telemanipulation of Small-Scale Environments", ASME, Dynamic Systems and Control Div., 1998, 64, 213-218.
mp	A94	Koseki, Y. et al.; "Design and Accuracy Evaluation of High-Speed and High Precision Parallel Mechanism", Proc. of IEEE, Intl. Conf. on Robotics & Automation, 1998, 1340-1345.
mp	A95	Kim, Won-Jong; Trumper, David; "High Precision Magnetic Levitation Stage for Photolithography", Precision Engineering, 1998, 22, 66-77.
trub	A96	Mansky, P. et al.; "Large-Area Domain Alignment in Block Copolymer Thin Films Using Electric Fields", Macromolecules, 1998, 31, 4399-4401.
7000	A97	Wang, W.; Loh, R.; Gu, E.; "Passive Compliance Versus Active Compliance in Robot-Based Automated Assembly Systems", Industrial Robot, 1998, 25, 48-57.
imy	A98	Scheer, H.C. et al.; "Problems of Nanoimprinting Technique for Nanometer Scale Pattern Definition", Journal of Vacuum Science and Technology, 1998, 16, 3917-3921.
mi	A99	Xia, Y.; Whitesides, George; "Soft Lithography", Annu. Rev. Mater. Sci., 1998, 28, 153-184.
mo	A100	Tajbakhsh, H. et al.; "Three-Degree-of-Freedom Optic Mount for Extreme Ultraviolet Lithography", ASPE, 1998, 18, 359-362.
amo	A101	Lee, Dong Sung et al.; "Ultra Precision Positioning System for Servo Motor-Piezo Actuator Using Dual Servo Loop and Digital Filter Implementation", ASPE, 1998, 18, 287-290.
my	A102	Wu, Wei et al.; "Large Area High Density Quantized Magnetic Disks Fabricated Using Nanoimprint Lithography", 1998, Journal of Vacuum Science and Technology, 1998, 16, 3825-3829.
mo	A103	Ohya, Y. et al.; "Development of 3-DOF Finger Module for Micro Manipulation", Proc. of IEEE, Intl. Conf. on Intelligent Robots and Systems, 1999, 894-899.
Tony	A104	Tanikawa, T. et al.; "Development of Small-Sized 3 DOF Finger Module in Micro Hand for Micro Manipulation", Proc. of IEEE, Intl. Conf. on Intelligent Robots and Systems, 1999, 876-881.
am	A105	Colburn, M. et al.; "Step and Flash Imprint Lithography: New Approach to High-Resolution Patterning", Proc. of SPIE, 1999, 3676, 379-389.

EXAMINER:

DATE CONSIDERED:

List o	Form PTO-1449 (modified) List of Patents and Publications 2 1 2002 For Applicant's Information Disclosure Statement (Use several sheets if necessary) FILING DATE: October 25 100 100						
Dmn	A106						
tmo	A107	Goldfarb, M.; Speich, J.E.; "A Well-Behaved Revolute Flexure Joint for Compliant Mechanism Design", Journal of Mech. Design, 1999, 121, 424-429.					
my	A108	Geodetic Technology, G1000-PS Power Series Specifications, 1999, from www.hexapods.com					
mp	A109	Hexel Corporation, Tornado 2000 System Specifications, 1999, from www.hexel.com					
· FMD	A110	Physik Instruments, PI Online-Catalog, 1999, from www.physikinstruments.com					
mb	A111	Chou, Stephen; Zhuang, Lei; "Lithographically-induced Self Assembly of Periodic Micropillar Arrays", Journal of Vacuum Science and Technology, 1999, 17, 3197-3202.					
mo	A112	Ruchhoeft, P. et al.; "Patterning Curved Surfaces: Template Generation by Ion Beam Proximity Lithography and Relief Transfer by Step and Flash Imprint Lithography", Journal of Vacuum Science and Technology, 1999, 17, 2965-2982.					
MM	A113	Vanderbilt University Office of Transfer Technology; VU 9730 Specifications for Improved Flexure Device; 2001, from www.vanderbilt.edu					
M	A114	Stix, Gary; "Getting More from Moore's", Scientifc American, 2001, from www.scientificamerican.com					
mb	A115	Trilogy Systems, Linear Motors 310 Specification, 2001, from www.trilogysystems.com					
my	A116	Choi, B.J. et al.; "Design of Orientation Stages for Step and Flash Imprint Lithography", Precision Engineering, 2001, 25, 192-199.					
m	A117	PCT International Search Report for PCT/US 00/30041, dated 10/15/2001					
and	A118	PCT International Search Report for PCT/US 01/26049, dated 2/19/2002					

EXAMINER: Thomas M. Considered: Del. 13, 2004

Notice of References Cited Application/Control No. 09/698,317 Examiner Thomas M. Dougherty Applicant(s)/Patent Under Reexamination CHOI ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,772,905 A	06-1998	Chou, Stephen Y.	216/44
*	В	US-6,411,010 B1	06-2002	Suzuki et al.	310/323.17
*	С	US-5,063,321	11-1991	Carter, Robert E.	310/323.17
*	D	US-3,527,062	09-1970	BILINSKI DONALD J; et. al.	464/78
*	E	US-6,188,150 B1	02-2001	Spence, Paul A.	310/12
*	F	US-6,467,761 B1	10-2002	Amatucci et al.	269/58
*	G	US-5,270,984 A	12-1993	Mine, Kazuhiro	367/140
	Ξ	US-			
	-	US-			
	7	US-			
	K	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.